

PATENT

IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

Applicant : Michael P. Chrisp Docket No. : IL-11127
Serial No. : Art Unit :
Filed : Examiner :
For : COMPACT REFLECTIVE IMAGING SPECTROMETER
UTILIZING IMMERSED GRATINGS

INFORMATION DISCLOSURE STATEMENT

Commissioner for Patents
Alexandria, VA 22313-1450

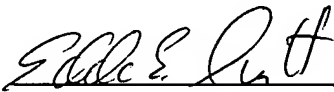
Dear Sir:

Forwarded herewith is an Information Disclosure Statement, Form-1449, in the above-identified application. Copies of the cited references are enclosed: 14 U.S. Patent Documents and 1 Foreign Patent Document.

The above-mentioned disclosures, which are not admitted as prior art, are identified on the enclosed Form 1449.

Respectfully submitted,

Dated: September 8, 2003


Eddie E. Scott
Attorney for Applicant
Registration No. 25,220

Enclosures: As noted above

Please type a plus sign (+) inside this box +

PTO/SB/08A (08-00)

Approved for use through 10/31/2002. OMB 0651-0031

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Substitute for form 1449A/PTO INFORMATION DISCLOSURE STATEMENT BY APPLICANT (use as many sheets as necessary)				Complete if Known		
				Application Number		
				Filing Date		
				First Named Inventor		
				Group Art Unit		
				Examiner Name		
Sheet	1	of	1	Attorney Docket Number		IL-11127

U.S. PATENT DOCUMENTS

Examiner Initials*	Cite No. ¹	U.S. Patent Document Number	Kind Code ² (if known)	Name of Patentee or Applicant of Cited Document	Date of Publication of Cited Document MM-DD-YYYY	Pages, Columns, Lines, Where Relevant Passages or Relevant Figures Appear
		5,127,728		Warren, et al.	07-07-1992	
		5,717,487		Davies	01-10-1998	
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		6,266,140	B1	Xiang, et al.	07-24-2001	
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FOREIGN PATENT DOCUMENTS

Examiner Initials*	Cite No. ¹	Foreign Patent Document Office ³	Number ⁴	Kind Code ⁵ (if known)	Name of Patentee or Applicant of Cited Document	Date of Publication of Cited Document MM-DD-YYYY	Pages, Columns, Lines, Where Relevant Passages or Relevant Figures Appear	T ⁶
			WO 99/63311		Ansley, et al.	12-09-1999		

Examiner Signature		Date Considered	
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¹ Unique citation designation number. ² See attached Kinds of U.S. Patent Documents. ³ Enter Office that issued the document, by the two-letter code (WIPO Standard ST.3). ⁴ For Japanese patent documents, the indication of the year of the reign of the Emperor must precede the serial number of the patent document. ⁵ Kind of document by the appropriate symbols as indicated on the document under WIPO Standard ST. 16 if possible. ⁶ Applicant is to place a check mark here if English language Translation is attached.
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